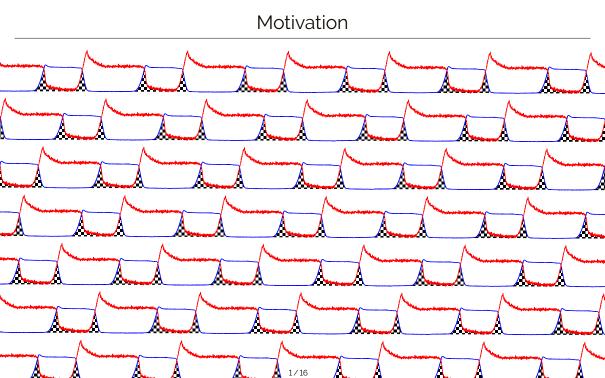


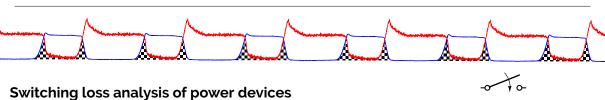
oisson & Drift-Diffusion Equations Solver for Semiconductor Device Modelling

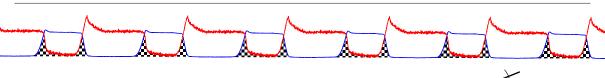
J. Miklas (jan.miklas@vut.cz) P. Prochazka (prochazkap@vut.cz)
Brno University of Technology , Czech Republic

FEniCS 2023, June 14-16



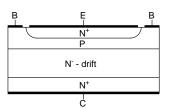


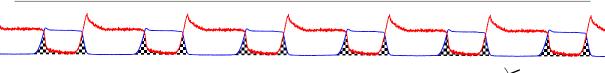




Switching loss analysis of power devices

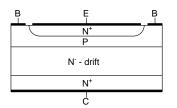
• High voltage, high current

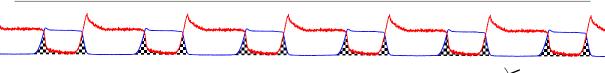




Switching loss analysis of power devices

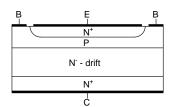
- High voltage, high current
- Excess charge storage in bipolar transistors (BJT, IGBT) during on-state





Switching loss analysis of power devices

- High voltage, high current
- Excess charge storage in bipolar transistors (BJT, IGBT) during on-state
 - 1-D lumped charge models (possibly transient?)



-emiconductor Equations - Full Drift-Diffusion Model

(1)

(3)

(4)

(5)

Electrostatics (Gauss's Law): Poisson's Equation:

$$\nabla \cdot (\varepsilon \nabla \psi) = -q(p - n + N_D - N_A)$$

Carrier transport: drift-diffusion equations:

$$\mathbf{J}_{p} = \overbrace{qp\mu_{p}\mathbf{E}}^{\text{drift}} - \overbrace{qD_{p}\nabla p}^{\text{diffusion}}$$

$$\mathbf{J}_n = qn\mu_n\mathbf{E} + qD_n\nabla n$$

Continuity equations

$$\frac{\partial p}{\partial t} = -\frac{1}{q} \nabla \cdot \mathbf{J}_p - R$$

$$\frac{\partial n}{\partial t} = \frac{1}{q} \nabla \cdot \mathbf{J}_n - R$$

Shockley-Read-Hall (SRH) recombination

$$R = \frac{n \cdot p - n_i^2}{\tau_p(n + n_0) + \tau_n(p + p_0)}$$

Unknown variables $(\psi, p, n, \mathbf{J}_p, \mathbf{J}_n)$

(2) Notation: $\frac{\varepsilon}{\varepsilon}$

Permittivity of material (silicon)
Electric potential

Electric field intensity $\mathbf{E} = -\nabla \psi$ Elementary charge

p, n Holes and electrons concentration

Holes and electron current density

 J_p , J_n Hole and electron current density N_A, N_D Acceptors and donors concentration μ_p, μ_n hole and electron mobility

Diffusion constants (Fick's Law)
Recombination-generation rate

 n_i Intrinsic carrier concentration p_0, n_0 thermal equillibrium concentrations τ_p, τ_n hole and electron recombination lifetime

(6)

Semiconductor Equations - 3 equations system

• 3 independent variables (ψ, p, n)

$$\lambda_0 \nabla \cdot (\nabla \psi) = -(p - n + N_D - N_A) \tag{7}$$

$$\frac{1}{\lambda_1} \frac{\partial p}{\partial t} = 0 = \nabla \cdot (\mu_p \ p \ \nabla \psi + D_p \ \nabla p) - R(p, n)$$
 (8)

$$\frac{1}{\lambda_1} \frac{\partial n}{\partial t} = O = \nabla \cdot (\underbrace{-\mu_n \, n \, \nabla \psi}_{\text{Diff}} + \underbrace{D_n \, \nabla n}_{\text{Diffusion}}) - \underbrace{R(p, n)}_{\text{Recombination}}$$
(9)

Semiconductor Equations - 3 equations system

• 3 independent variables (ψ, p, n)

$$\lambda_0 \nabla \cdot (\nabla \psi) = -(p - n + N_D - N_A) \tag{7}$$

$$\frac{1}{\lambda_1} \frac{\partial p}{\partial t} = 0 = \nabla \cdot (\mu_p \ p \ \nabla \psi + D_p \ \nabla p) - R(p, n)$$
 (8)

$$\frac{1}{\lambda_1} \frac{\partial n}{\partial t} = 0 = \nabla \cdot \left(\underbrace{-\mu_n \ n \ \nabla \psi}_{\text{Drift}} + \underbrace{D_n \ \nabla n}_{\text{Diffusion}} \right) - \underbrace{R(p, n)}_{\text{Recombination}}$$
(9)

- Scaled
- Coupled
- Nonlinear

Steady State Problem Statement

$$\lambda_0 \nabla \cdot (\nabla \psi) = -(p - n + N_D - N_A) \quad \text{in } \Omega$$
 (10)

$$O = \nabla \cdot (\rho \mu_{\rho} \nabla \psi + D_{\rho} \nabla \rho) - R \qquad \text{in } \Omega$$

$$O = \nabla \cdot (-n\mu_n \nabla \psi + D_n \nabla n) - R \qquad \text{in } \Omega$$
(12)

with "ohmic" boundary conditions

$$\psi = \psi_{\mathrm{BC}}$$
 on Γ_{D0} (13)

(11)

(14)

(15)

$$p = p_{\rm BC}$$
 on $\Gamma_{\rm D1}$

$$n = n_{\rm BC}$$
 on $\Gamma_{\rm D2}$

$$\mathbf{n} \cdot \nabla \psi = g \qquad \text{on } \Gamma_{\text{N0}} \tag{16}$$

Variational Formulation

$$\lambda_0 \nabla \cdot (\nabla \psi) = -(p - n + N_D - N_A) \quad \text{in } \Omega$$
 (10)

$$O = \nabla \cdot (\rho \mu_{\rho} \nabla \psi + D_{\rho} \nabla \rho) - R \qquad \text{in } \Omega$$

$$O = \nabla \cdot (-n\mu_n \nabla \psi + D_n \nabla n) - R \qquad \text{in } \Omega$$
(12)

Find $(\psi, p, n) \in V_0 \times V_1 \times V_2$ such that

$$F((\psi, p, n); (v_0, v_1, v_2)) = 0$$
(17)

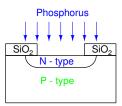
(11)

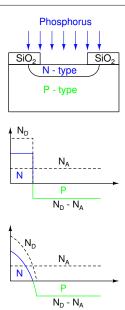
for all $(v_0, v_1, v_2) \in \hat{V}_0 \times \hat{V}_1 \times \hat{V}_2$; with F given by:

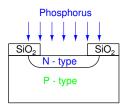
$$F = -\int_{\Omega} \lambda_{0} \nabla \psi \cdot \nabla v_{0} \, dx + \int_{\Omega} (p - n + N_{D} - N_{A}) v_{0} \, dx + \int_{\Gamma_{NO}} g v_{0} \, ds$$

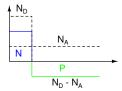
$$-\int_{\Omega} D_{p} \nabla p \cdot \nabla v_{1} \, dx - \int_{\Omega} \mu_{p} p \nabla \psi \cdot \nabla v_{1} \, dx - R v_{1} \, dx$$

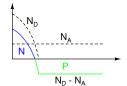
$$-\int_{\Omega} D_{n} \nabla n \cdot \nabla v_{2} \, dx + \int_{\Omega} \mu_{n} n \nabla \psi \cdot \nabla v_{2} \, dx - R v_{2} \, dx$$
(18)



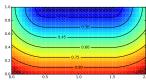


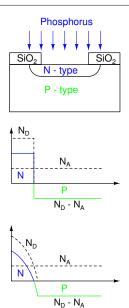


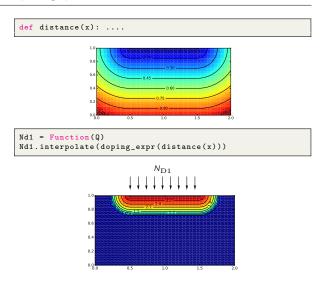


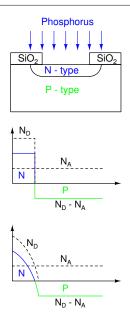


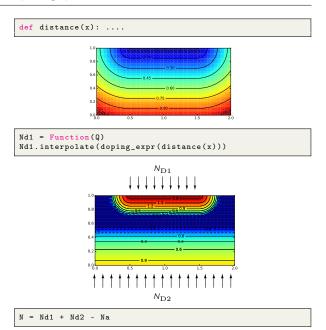






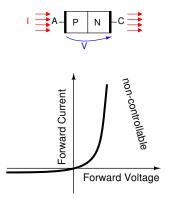




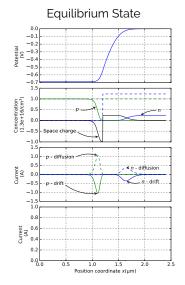




Typical Electrical Output Characteristics



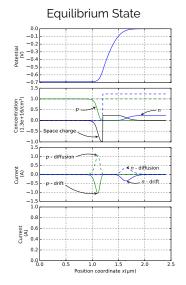
Simulation Results - Step junction



Reverse / Zero Bias:

- Depletion region formed
- Zero total current
- Drift compensated by diffusion

Simulation Results - Step junction

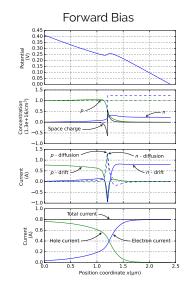


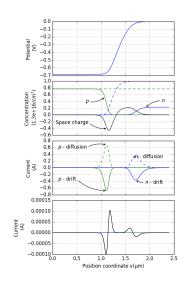
Reverse / Zero Bias:

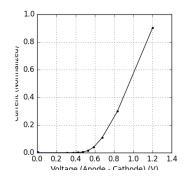
- Depletion region formed
- Zero total current
- Drift compensated by diffusion

Forward Bias:

- Depletion region reduced
- Constant current across device
- · minority carriers injected
- majority carriers exceeding doping concentration



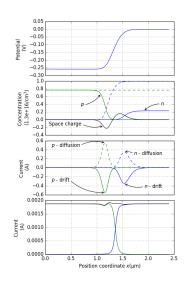


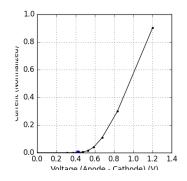


$$\lambda_{0}\nabla \cdot (\nabla \psi) = -(p - n + N_{D} - N_{A})$$

$$0 = \nabla \cdot (p\mu_{p}\nabla \psi + D_{p}\nabla p) - R$$

$$0 = \nabla \cdot (-n\mu_{0}\nabla \psi + D_{0}\nabla n) - R$$

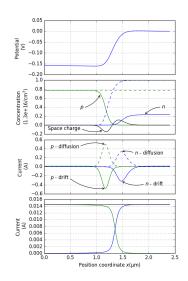


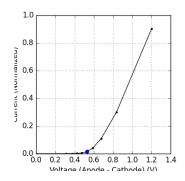


$$\lambda_0 \nabla \cdot (\nabla \psi) = -(p - n + N_D - N_A)$$

$$O = \nabla \cdot (p \mu_p \nabla \psi + D_p \nabla p) - R$$

$$O = \nabla \cdot (-n \mu_0 \nabla \psi + D_0 \nabla n) - R$$

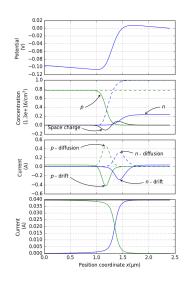


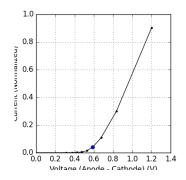


$$\lambda_{0}\nabla\cdot(\nabla\psi) = -(p - n + N_{D} - N_{A})$$

$$0 = \nabla\cdot(p\mu_{p}\nabla\psi + D_{p}\nabla p) - R$$

$$0 = \nabla\cdot(-n\mu_{n}\nabla\psi + D_{n}\nabla n) - R$$

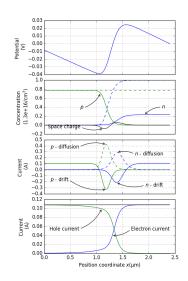


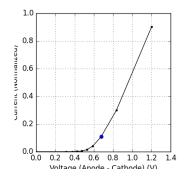


$$\lambda_{0}\nabla\cdot(\nabla\psi) = -(p - n + N_{D} - N_{A})$$

$$O = \nabla\cdot(p\mu_{p}\nabla\psi + D_{p}\nabla p) - R$$

$$O = \nabla\cdot(-n\mu_{n}\nabla\psi + D_{n}\nabla n) - R$$

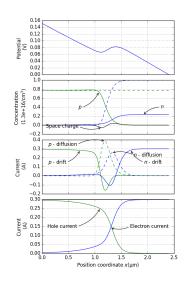


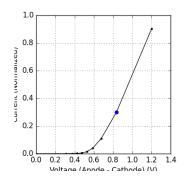


$$\lambda_{0}\nabla\cdot(\nabla\psi) = -(p - n + N_{D} - N_{A})$$

$$O = \nabla\cdot(p\mu_{p}\nabla\psi + D_{p}\nabla p) - R$$

$$O = \nabla\cdot(-n\mu_{n}\nabla\psi + D_{n}\nabla n) - R$$

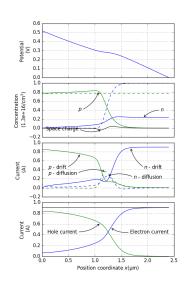


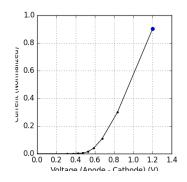


$$\lambda_{0}\nabla\cdot(\nabla\psi) = -(p - n + N_{D} - N_{A})$$

$$0 = \nabla\cdot(p\mu_{p}\nabla\psi + D_{p}\nabla p) - R$$

$$0 = \nabla\cdot(-n\mu_{n}\nabla\psi + D_{n}\nabla n) - R$$



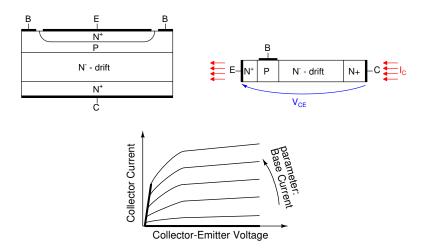


$$\lambda_{O} \nabla \cdot (\nabla \psi) = -(p - n + N_{D} - N_{A})$$

$$O = \nabla \cdot (p \mu_{p} \nabla \psi + D_{p} \nabla p) - R$$

$$O = \nabla \cdot (-n \mu_{D} \nabla \psi + D_{D} \nabla n) - R$$

Typical Electrical Output Characteristics



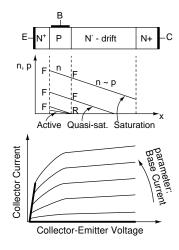
1-D Lumped Charge Model

- Charge control + conductivity modulation
- "Rules":
 - Zero mobile carriers at reverse biased junction
 - Some mobile charge at forward biased junction
 - defined by applied voltage and doping concentrations
 - Diffusion current: defined by concentration gradient
 - Conductivity: defined by amount of mobile carriers

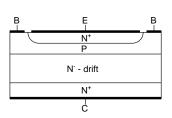
Equations (2),(3)

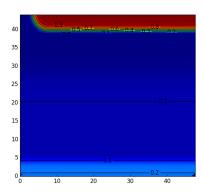
$$\mathbf{J}_{p} = \overrightarrow{qp\mu_{p}}\mathbf{E} - \overrightarrow{qD_{p}}\nabla p$$

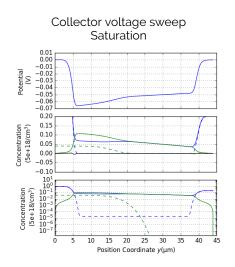
$$\mathbf{J}_{n} = qn\mu_{n}\mathbf{E} + qD_{n}\nabla n$$

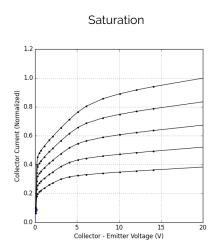


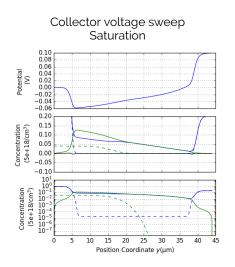
Simulation Domain, BC, Doping

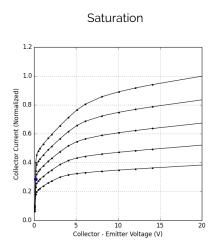


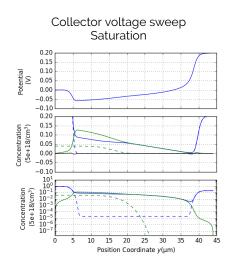


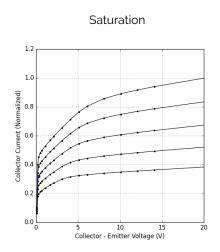


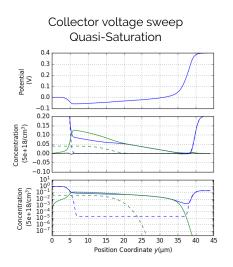


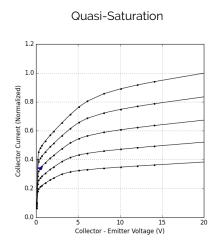


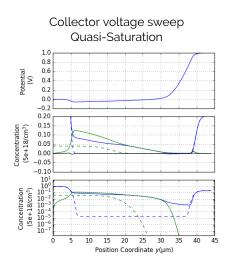


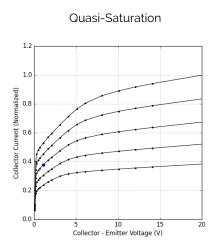


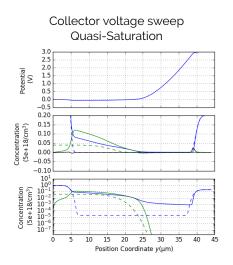


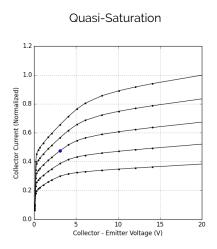


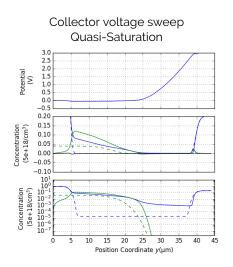


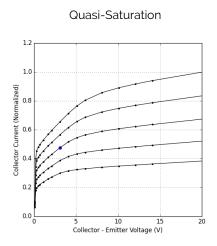


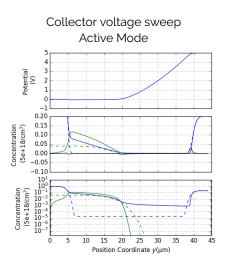


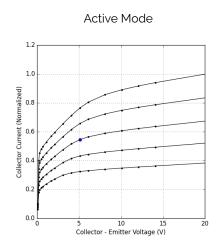


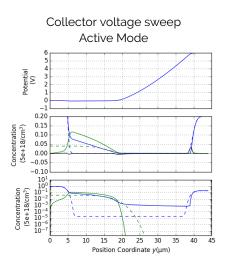


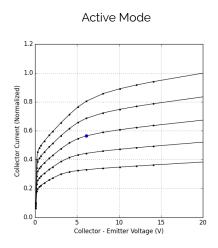


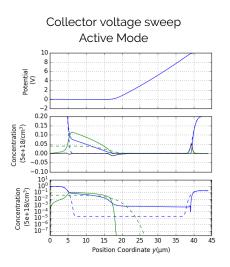


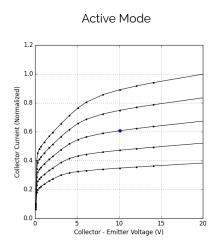


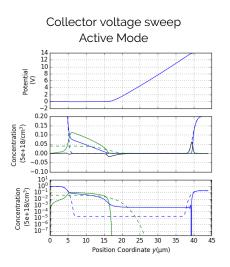


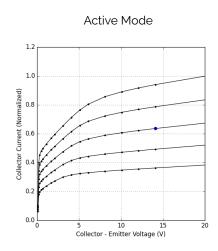


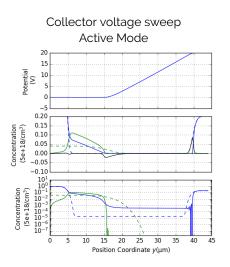


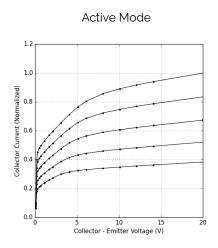


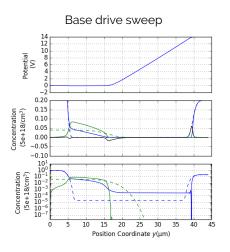


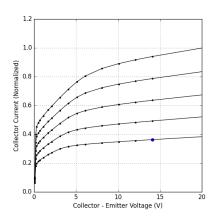


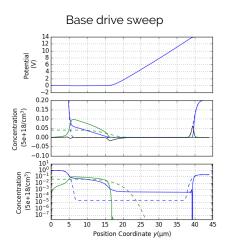


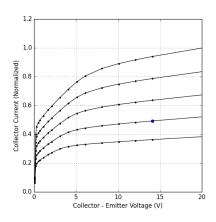


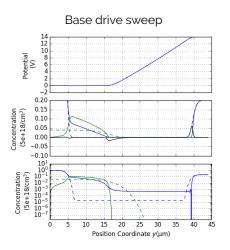


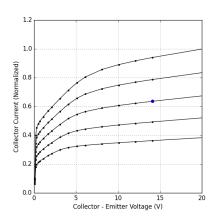


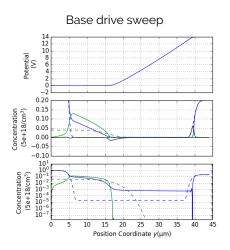


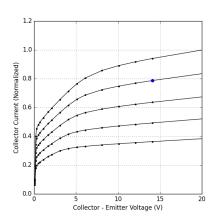


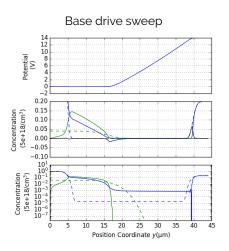


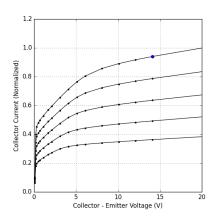


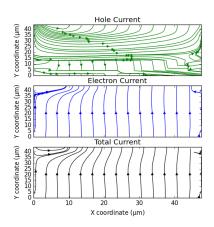


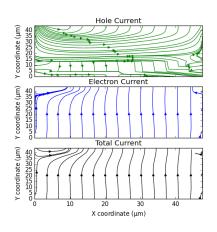


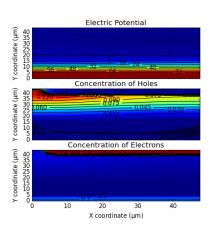












Summary

- Numerical approach validated and demonstrated on basic structures
 - The equations and FEniCS seem to love each other
- Currently in "demo version" qualitative explanation of device physics
- Good validation tool for analytical assumptions in simplified power BJT model

Outlook

Space for improvements:

- Time dependent problem
- Initial guess accuracy, BC for any bias
- Nonlinear Solver, Convergence, Stability

https://github.com/janmiklas/fenicsx-semiconductor-eq

Thank you for your kind attention!